

HMIC™ Silicon Beam-Lead PIN Diodes

**MA4PBL027
V1**

Features

- Beam-Lead Device
- No Wirebonds Required
- Rugged Silicon-Glass Construction
- Silicon Nitride Passivation
- Polymer Scratch and Impact Protection
- Low Parasitic Capacitance and Inductance
- Ultra Low Capacitance < 40 fF
- Excellent RC Product < 0.10 pS
- High Switching Cutoff Frequency > 110 GHz
- 110 Nanosecond Minority Carrier Lifetime
- Driven by Standard +5V TTL PIN Diode Driver

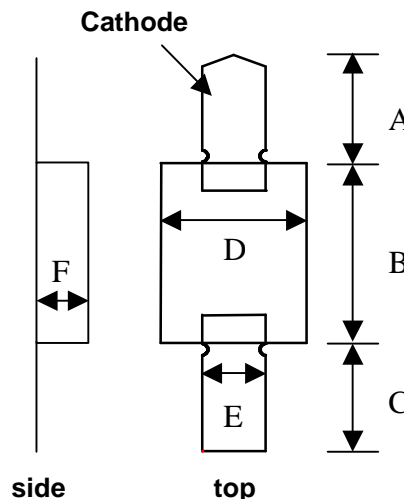
Description and Applications

This device is a Silicon-Glass Beam-Lead PIN diode fabricated with M/A-COM's patented HMIC™ process. This device features one silicon pedestal embedded in a low loss, low dispersion glass which supports the beam-leads. The diode is formed on the top of the pedestal, and airbridges connect the diode to the beam-leads. The topside is fully encapsulated with silicon nitride and has an additional polymer layer for scratch and impact protection. These protective coatings prevent damage to the junction and the air-bridges during handling and assembly.

The diodes themselves exhibit low series resistance, low capacitance, and extremely fast switching speed.

The ultra low capacitance of this device allows use through W-band (110 GHz) applications. The low RC product and low profile of the PIN diodes makes it ideal for use in microwave and millimeter wave switch designs, where lower insertion loss and higher isolation are required. The + 10 mA (low loss state) and the 0v (isolation state) bias of the diodes allows the use a simple + 5V TTL gate driver. These diodes are used as switching arrays on radar systems, high-speed ECM circuits, optical switching networks, instrumentation, and other wideband multi-throw switch assemblies.

Case Style ODS-1302



Dimension	Mils	mm
A	9.3 +/- 2.0	0.24 +/- 0.05
B	15.3 +/- 2.0	0.39 +/- 0.05
C	9.3 +/- 2.0	0.24 +/- 0.05
D	12.6 +/- 2.0	0.32 +/- 0.05
E	5.5 +/- 2.0	0.14 +/- 0.05
F	5.0 +/- 1.0	0.13 +/- 0.03

Absolute Maximum Ratings @ T_A = +25 °C (unless otherwise specified)¹

Parameter	Maximum Rating
Forward Current	100 mA
Reverse Voltage	90 V
Operating Temperature	-55 °C to +125 °C
Storage Temperature	-55 °C to +150 °C
Junction Temperature	+175 °C
RF C.W. Incident Power	30 dBm C.W.
RF & DC Dissipated Power	150 mW
Mounting Temperature	+235°C for 10 sec.

1. Operation of this device above any one of these parameters may cause permanent damage.

Electrical Specifications at +25 °C

Symbol	Conditions	Units	Typ.	Max.
C _T	0 V, 1 MHz ²	pF	0.048	
C _T	-3 V, 1 MHz ²	pF	0.039	
C _T	-10 V, 1 MHz ²	pF	0.033	0.040
C _T	-40 V, 1 MHz ²	pF	0.030	0.040
C _T	0 V, 100 MHz ^{2,4}	pF	0.043	
C _T	-3 V, 100 MHz ^{2,4}	pF	0.033	
C _T	-10V, 100 MHz ^{2,4}	pF	0.031	
C _T	-40V, 100 MHz ^{2,4}	pF	0.027	
C _T	0 V, 1 GHz ^{2,4}	pF	0.039	
C _T	-3 V, 1 GHz ^{2,4}	pF	0.032	
C _T	-10 V, 1 GHz ^{2,4}	pF	0.029	
C _T	-40 V, 1 GHz ^{2,4}	pF	0.026	
R _S	10 mA, 100 MHz ^{3,4}	Ω	3.8	
R _S	20 mA, 100 MHz ^{3,4}	Ω	3.0	
R _S	10 mA, 1 GHz ^{3,4}	Ω	3.5	
R _S	20 mA, 1 GHz ^{3,4}	Ω	2.8	
V _F	20 mA	V	0.917	1.1
V _R	-10 μA	V	110	
I _R	-40 V	nA	1.0	
I _R	-90 V	μA	-	10.0
T _L	+10 mA / -6 mA	ns	110	

NOTES:

- Total capacitance, C_T, is equivalent to the sum of Junction Capacitance ,C_J, and Parasitic Capacitance, C_{par}.
- Series resistance R_S is equivalent to the total diode resistance : R_S = R_j (Junction Resistance) + R_c (Ohmic Resistance)
- R_s and C_T are measured on an HP4291A Impedance Analyzer with die mounted in an ODS-186 package with conductive silver epoxy.

Die Handling

All semiconductor chips should be handled with care to avoid damage or contamination from perspiration and skin oils. The use of plastic tipped tweezers or vacuum pickups is strongly recommended for individual components. Bulk handling should insure that abrasion and mechanical shock are minimized.

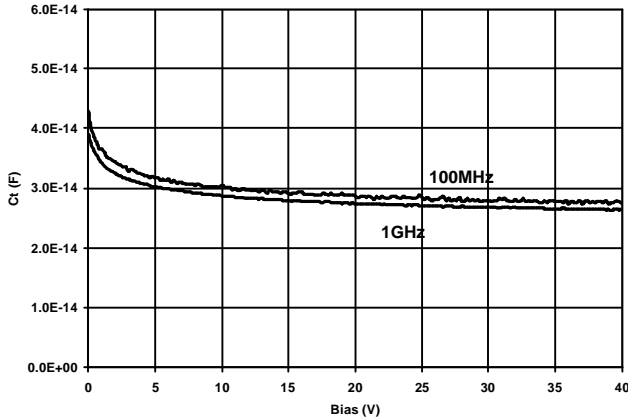
Die Bonding

These devices were designed to be inserted onto hard or soft substrates. Recommended methods of attachment include thermocompression bonding, parallel-gap welding, and electrically conductive silver epoxy.

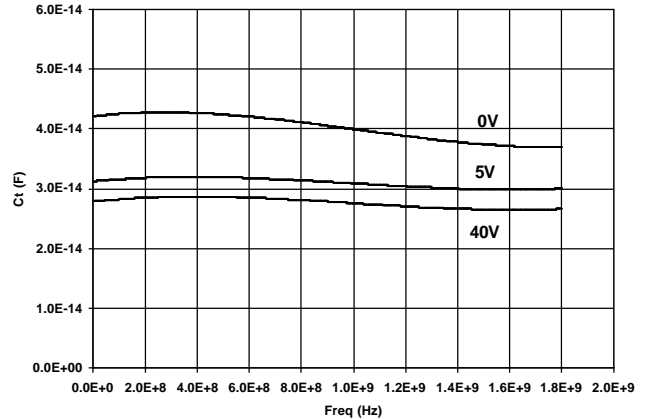
See Application Note M541, “Bonding and Handling Procedures for Chip Diode Devices” for More Detailed Assembly Instructions.

Typical Performance Curves @ +25°C

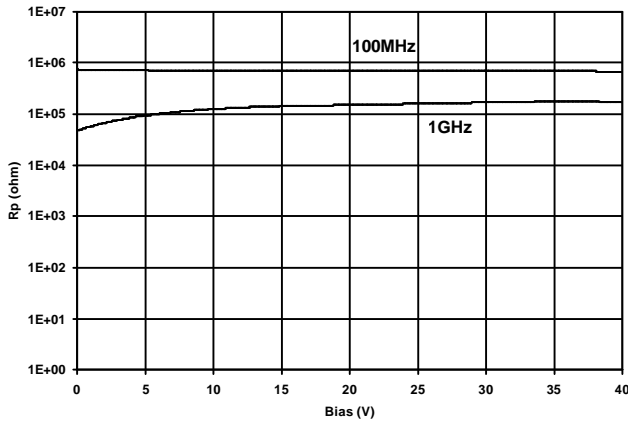
Total Capacitance C_t vs V



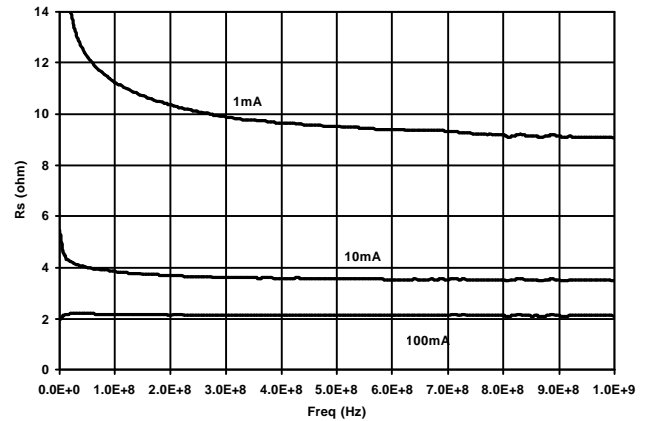
Total Capacitance C_t vs Freq



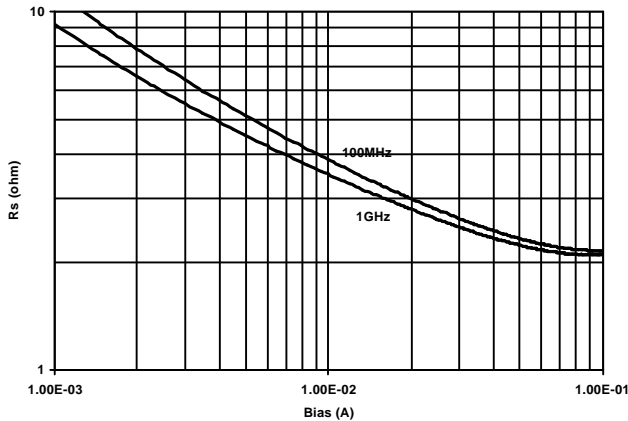
Parallel Resistance R_p vs V



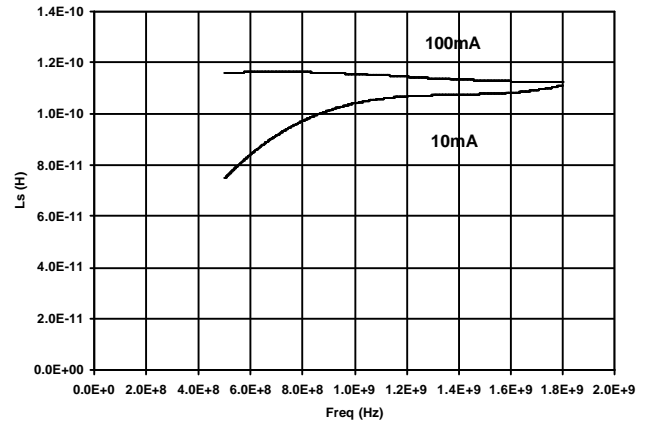
Series Resistance R_s vs F

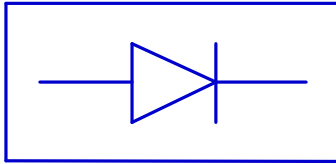


Series Resistance R_s vs I



Series Inductance L_s vs Freq





MA4PBL027 SPICE Model

PinDiodeModel

NLPINM1

Is=1.0E-14 A

Vi=0.0 V

Un= 900 cm²/V-sec

Wi= 14 um

Rr= 100 K Ohms

Cjmin= 0.03 pF

Tau= 110 nsec

Rs(I)= Rc + Rj(I) = 0.05 Ohm + Rj(I)

Cj0= 0.04 pF

Vj= 0.7 V

M= 0.5

Fc= 0.5

Imax= 1.1E+5 A/m²

Kf=0.0

Af=1.0

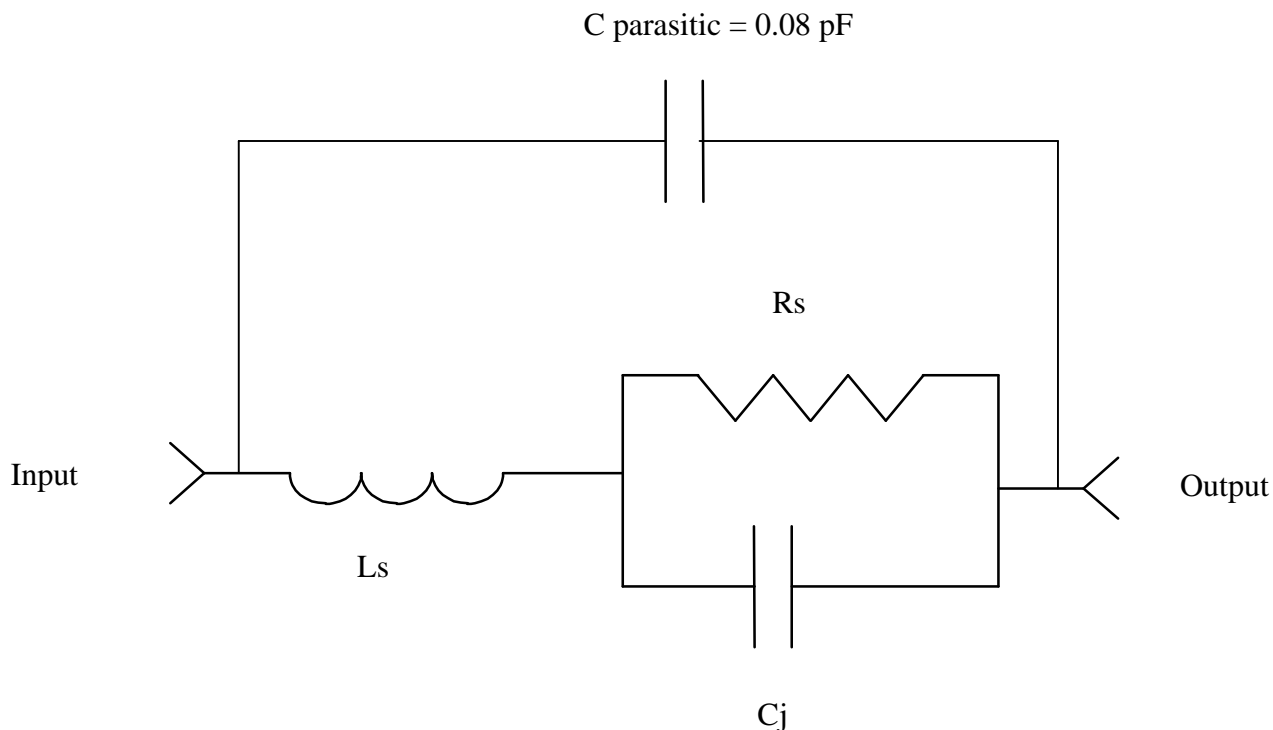
wBv= 90 V

wPmax= 150 mW

Ffe= 1.0

AllParams=

MA4PBL027 Microwave Model



Notes :

$$C_T(V) = C_j(V) + C_{\text{parasitic}} \text{ (Reverse Bias State)}$$

$$R_s(I) = R_j(I) + R_c \text{ (Forward Bias State)}$$

$$R_s(V) = R_j(V) = R_p(V) \text{ (Reverse Bias State)}$$